

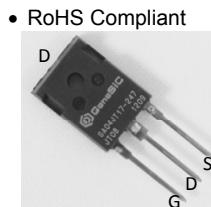
Normally – OFF Silicon Carbide Junction Transistor

V_{DS}	=	1700 V
V_{DS(ON)}	=	1.9 V
I_D	=	4 A
R_{DS(ON)}	=	480 mΩ

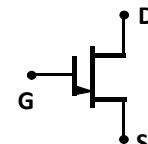
Features

- 175 °C maximum operating temperature
- Temperature independent switching performance
- Gate oxide free SiC switch
- Suitable for connecting an anti-parallel diode
- Positive temperature coefficient for easy paralleling
- Low gate charge
- Low intrinsic capacitance

Package



TO-247AB



Advantages

- Low switching losses
- Higher efficiency
- High temperature operation
- High short circuit withstand capability

Applications

- Down Hole Oil Drilling, Geothermal Instrumentation
- Hybrid Electric Vehicles (HEV)
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)
- Induction Heating
- Uninterruptible Power Supply (UPS)
- Motor Drives

Maximum Ratings unless otherwise specified

Parameter	Symbol	Conditions	Values	Unit
Drain – Source Voltage	V _{DS}	V _{GS} = 0 V	1700	V
Continuous Drain Current	I _D	T _{C,MAX} = 95 °C	4	A
Gate Peak Current	I _{GM}		5	A
Turn-Off Safe Operating Area	RBSOA	T _{VJ} = 175 °C, I _G = 1 A, Clamped Inductive Load	I _{D,max} = 4 @ V _{DS} ≤ V _{DSmax}	A
Short Circuit Safe Operating Area	SCSOA	T _{VJ} = 175 °C, I _G = 1 A, V _{DS} = 1200 V, Non Repetitive	20	μs
Reverse Gate – Source Voltage	V _{SG}		30	V
Reverse Drain – Source Voltage	V _{SD}		50	V
Power Dissipation	P _{tot}	T _C = 25 °C	91	W
Storage Temperature	T _{stg}		-55 to 175	°C

Electrical Characteristics at T_j = 175 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
On Characteristics						
Drain – Source On Voltage	V _{DS(ON)}	I _D = 4 A, I _G = 250 mA, T _j = 25 °C I _D = 4 A, I _G = 500 mA, T _j = 125 °C I _D = 4 A, I _G = 500 mA, T _j = 175 °C	1.9 3.3 4.5	2.3 4.0 5.5		V
Drain – Source On Resistance	R _{DS(ON)}	I _D = 4 A, I _G = 250 mA, T _j = 25 °C I _D = 4 A, I _G = 500 mA, T _j = 125 °C I _D = 4 A, I _G = 500 mA, T _j = 175 °C	480 830 1130			mΩ
Gate Forward Voltage	V _{GS(FWD)}	I _G = 500 mA, T _j = 25 °C I _G = 500 mA, T _j = 175 °C	3.3 3.2			V
DC Current Gain	β	V _{DS} = 5 V, I _D = 4 A, T _j = 25 °C V _{DS} = 5 V, I _D = 4 A, T _j = 175 °C	50	58 35		

Off Characteristics

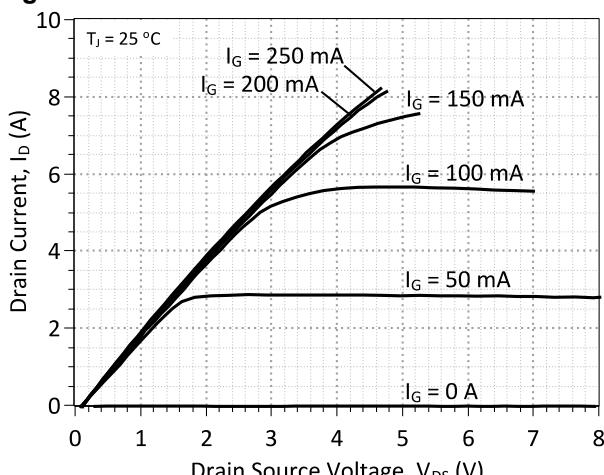
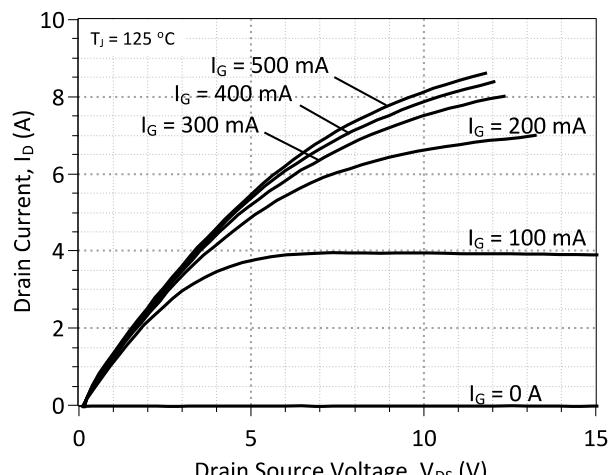
Drain Leakage Current	I _{DSS}	V _R = 1700 V, V _{GS} = 0 V, T _j = 25 °C V _R = 1700 V, V _{GS} = 0 V, T _j = 125 °C V _R = 1700 V, V _{GS} = 0 V, T _j = 175 °C	0.2 0.3 1.0	10 50 100	μA
Gate Leakage Current	I _{SG}	V _{SG} = 20 V, T _j = 25 °C	20		nA

Electrical Characteristics at $T_j = 175^\circ\text{C}$, unless otherwise specified

Parameter		Conditions		Values			
				min.	typ.	max.	Unit
Capacitance Characteristics							
Gate-Source Capacitance	C_{gs}	$V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		340			pF
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}, V_D = 1 \text{ V}, f = 1 \text{ MHz}$		460			pF
Reverse Transfer/Output Capacitance	C_{rss}/C_{oss}	$V_D = 1 \text{ V}, f = 1 \text{ MHz}$		120			pF
Switching Characteristics							
Turn On Delay Time	$t_{d(on)}$	$T_j = 25^\circ\text{C}$ "Option 2" Gate Driven $V_{DD} = 1100 \text{ V}, I_D = 4 \text{ A},$ $R_{G(on)} = R_{G(off)} = 22 \Omega,$ $V_{GS} = -8/15 \text{ V}, L = 1.1 \text{ mH},$ FWD = GB05SLT12, Refer to Figure 15 for gate current waveform		35			ns
Rise Time	t_r			28			ns
Turn Off Delay Time	$t_{d(off)}$			60			ns
Fall Time	t_f			50			ns
Turn-On Energy Per Pulse	E_{on}			323			μJ
Turn-Off Energy Per Pulse	E_{off}			60			μJ
Total Switching Energy	E_{ts}			383			μJ
Turn On Delay Time	$t_{d(on)}$			30			ns
Rise Time	t_r	$T_j = 175^\circ\text{C}$ "Option 2" Gate Driven $V_{DD} = 1100 \text{ V}, I_D = 4 \text{ A},$ $R_{G(on)} = R_{G(off)} = 22 \Omega,$ $V_{GS} = -8/15 \text{ V}, L = 1.1 \text{ mH},$ FWD = GB05SLT12, Refer to Figure 15 for gate current waveform		14			ns
Turn Off Delay Time	$t_{d(off)}$			73			ns
Fall Time	t_f			58			ns
Turn-On Energy Per Pulse	E_{on}			172			μJ
Turn-Off Energy Per Pulse	E_{off}			73			μJ
Total Switching Energy	E_{ts}			245			μJ

Thermal Characteristics

Thermal resistance, junction - case	R_{thJC}	1.64	$^\circ\text{C/W}$
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Figures

Figure 1: Typical Output Characteristics at 25°C

Figure 2: Typical Output Characteristics at 125°C

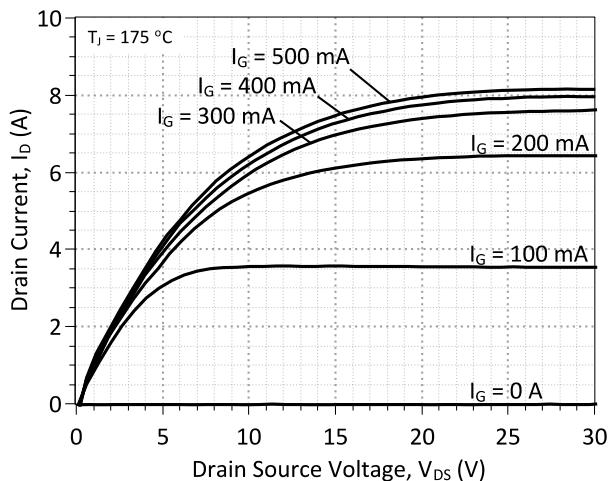


Figure 3: Typical Output Characteristics at 175°C

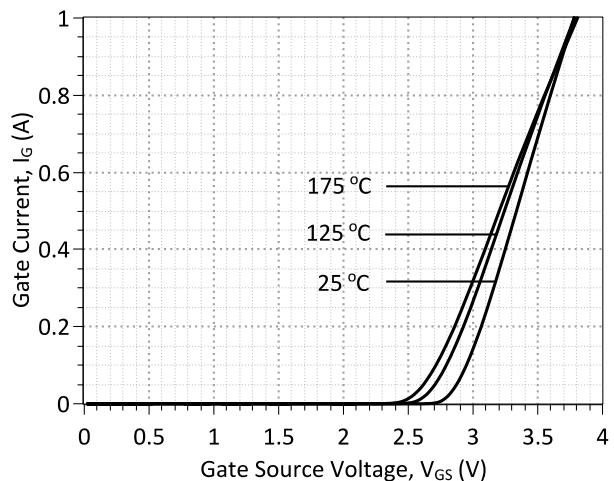


Figure 4: Typical Gate Source I-V Characteristics vs. Temperature

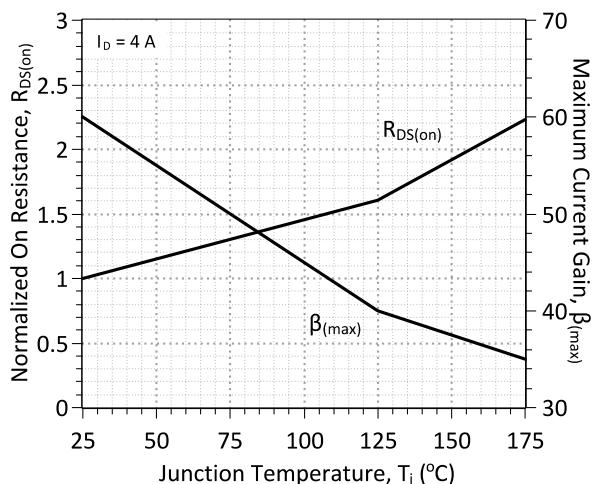


Figure 5: Normalized On-Resistance and Current Gain vs. Temperature

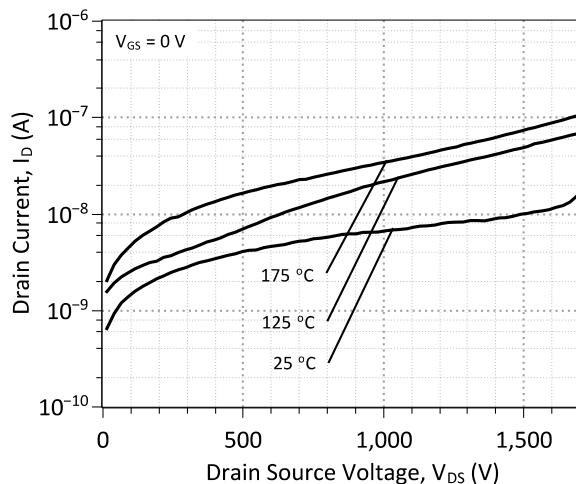


Figure 6: Typical Blocking Characteristics

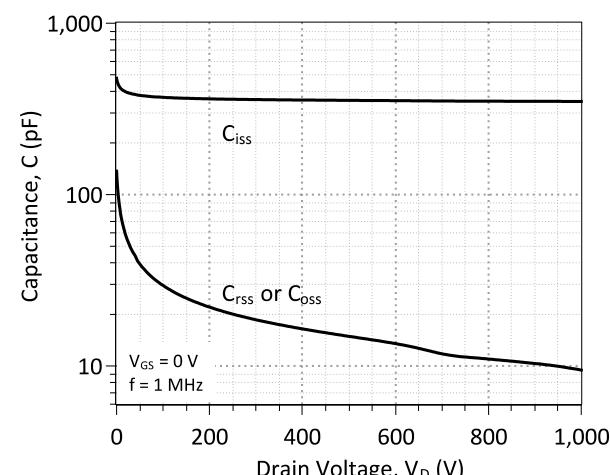


Figure 7: Capacitance Characteristics

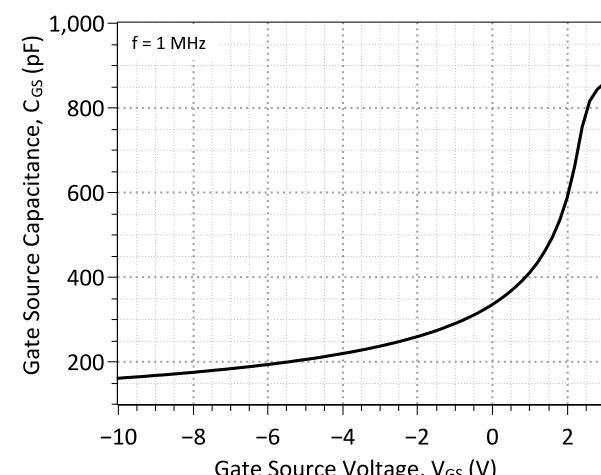


Figure 8: Capacitance Characteristics

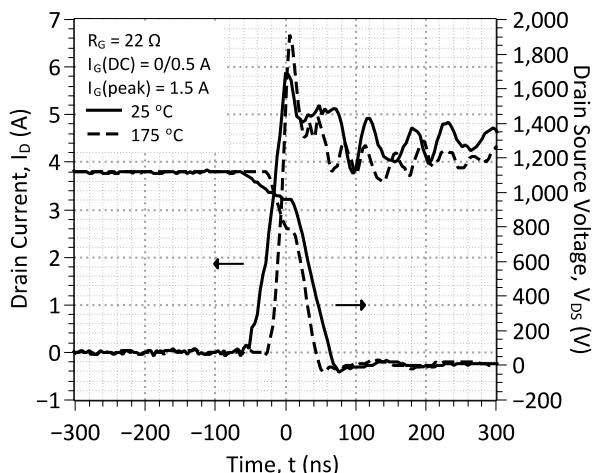


Figure 9: Typical Hard-switched Turn On Waveforms

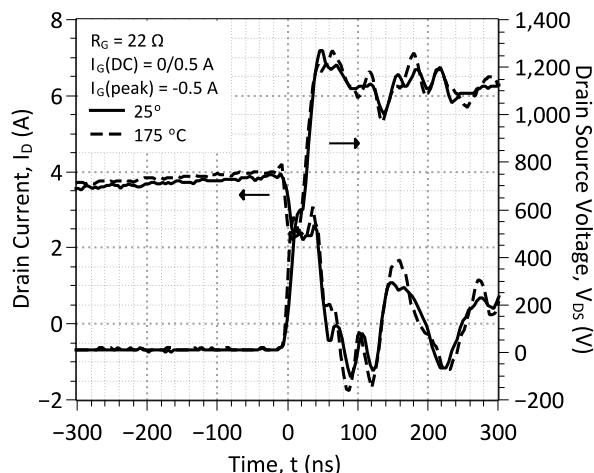


Figure 10: Typical Hard-switched Turn Off Waveforms

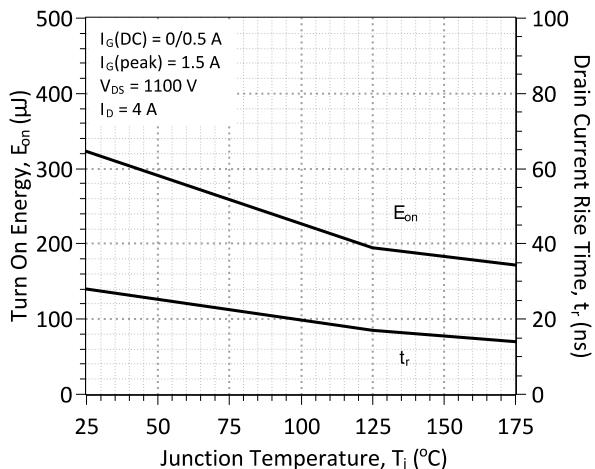


Figure 11: Typical Turn On Energy Losses and Switching Times vs. Temperature

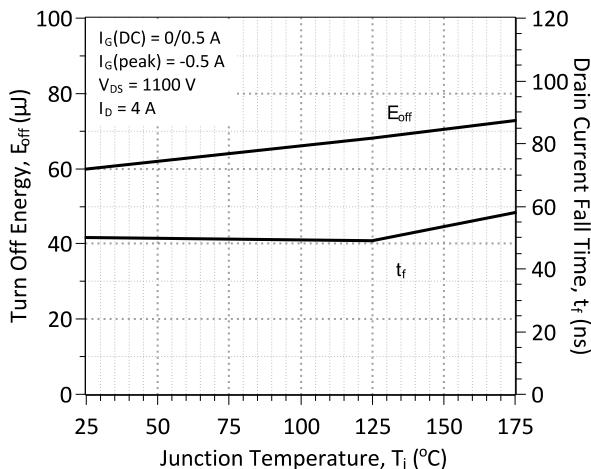


Figure 12: Typical Turn Off Energy Losses and Switching Times vs. Temperature

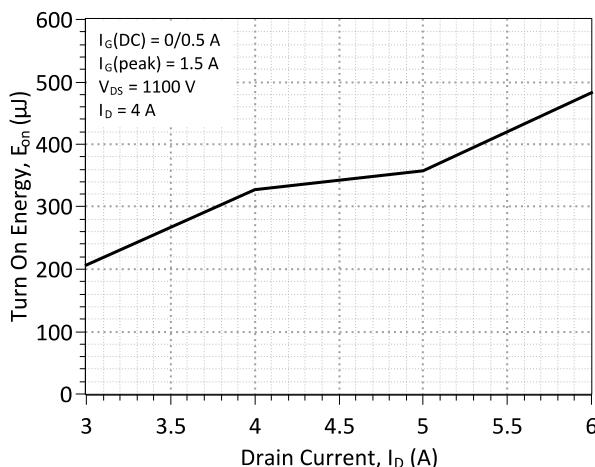


Figure 13: Typical Turn On Energy Losses vs. Drain Current

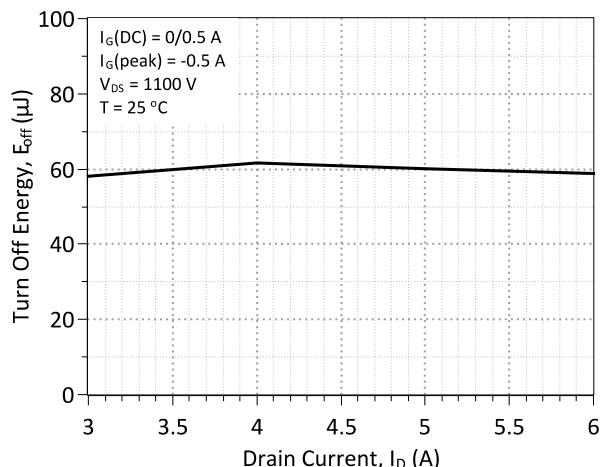


Figure 14: Typical Turn Off Energy Losses vs. Drain Current

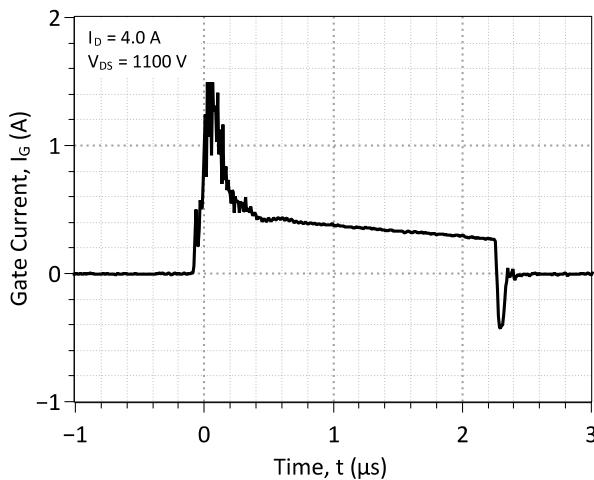


Figure 15: Typical Gate Current Waveform

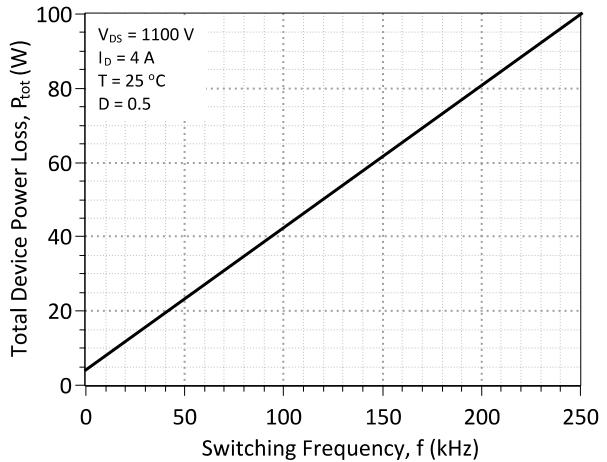


Figure 16: Typical Hard Switched Device Power Loss vs.
Switching Frequency¹

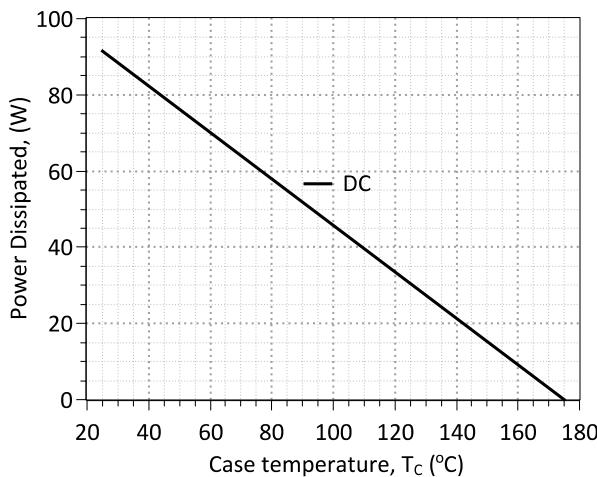


Figure 17: Power Derating Curve

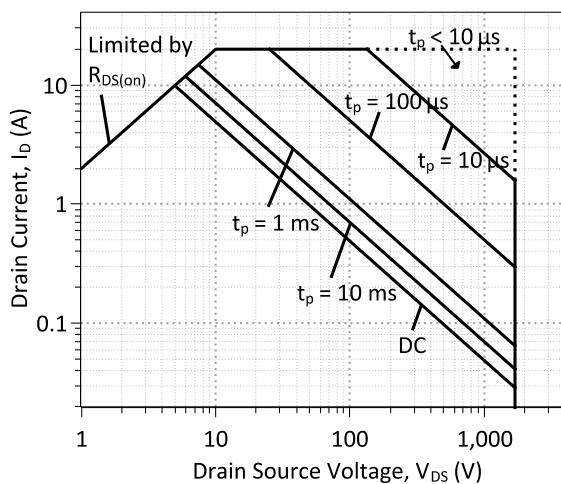


Figure 18: Forward Bias Safe Operating Area

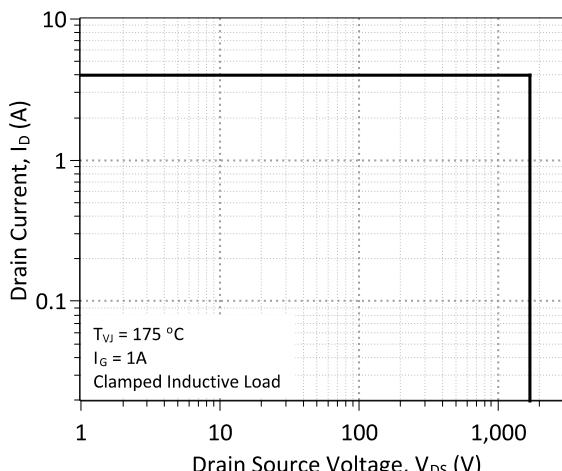


Figure 19: Turn-Off Safe Operating Area

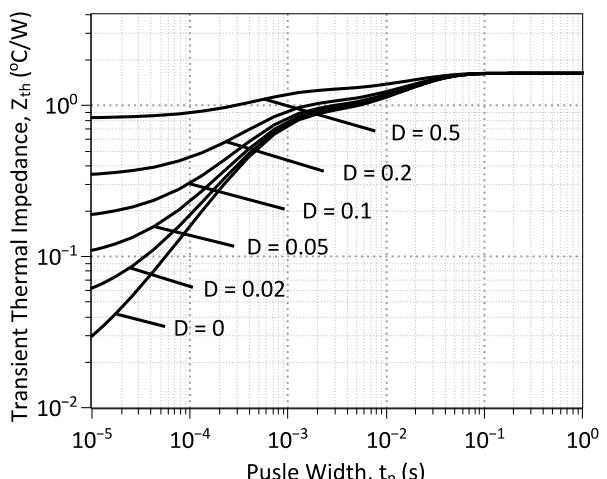


Figure 20: Transient Thermal Impedance

¹ – Representative values based on device switching energy loss. Actual losses will depend on gate drive conditions, device load, and circuit topology.

Gate Drive Technique (Option #1)

To drive the GA04JT17-247 with the lowest gate drive losses, please refer to the dual voltage source gate drive configuration described in Application Note AN-10B (<http://www.genesicsemi.com/index.php/references/notes>).

Gate Drive Technique (Option #2)

The GA04JT17-247 can be effectively driven using the IXYS IXdN614 / IXDD614 non-inverting gate driver IC or a comparable product. A typical gate driver configuration along with component values using this driver is offered below. Additional information is available in GeneSiC Application Note AN-10A and from the manufacturer at www.ixys.com.

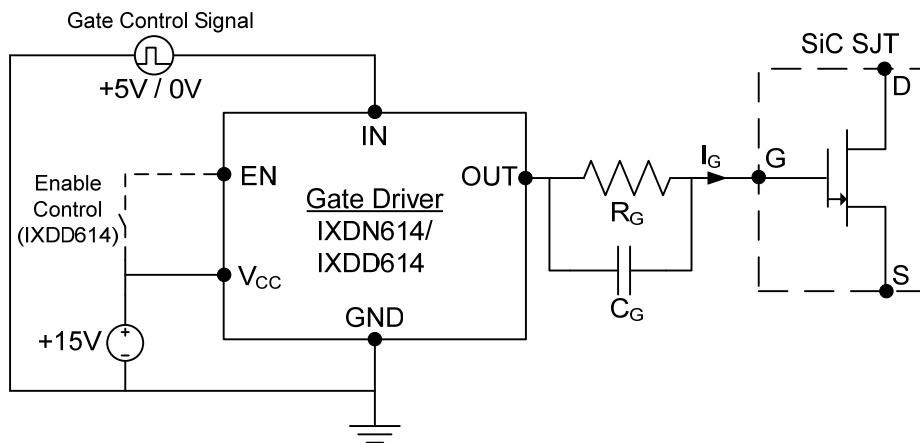


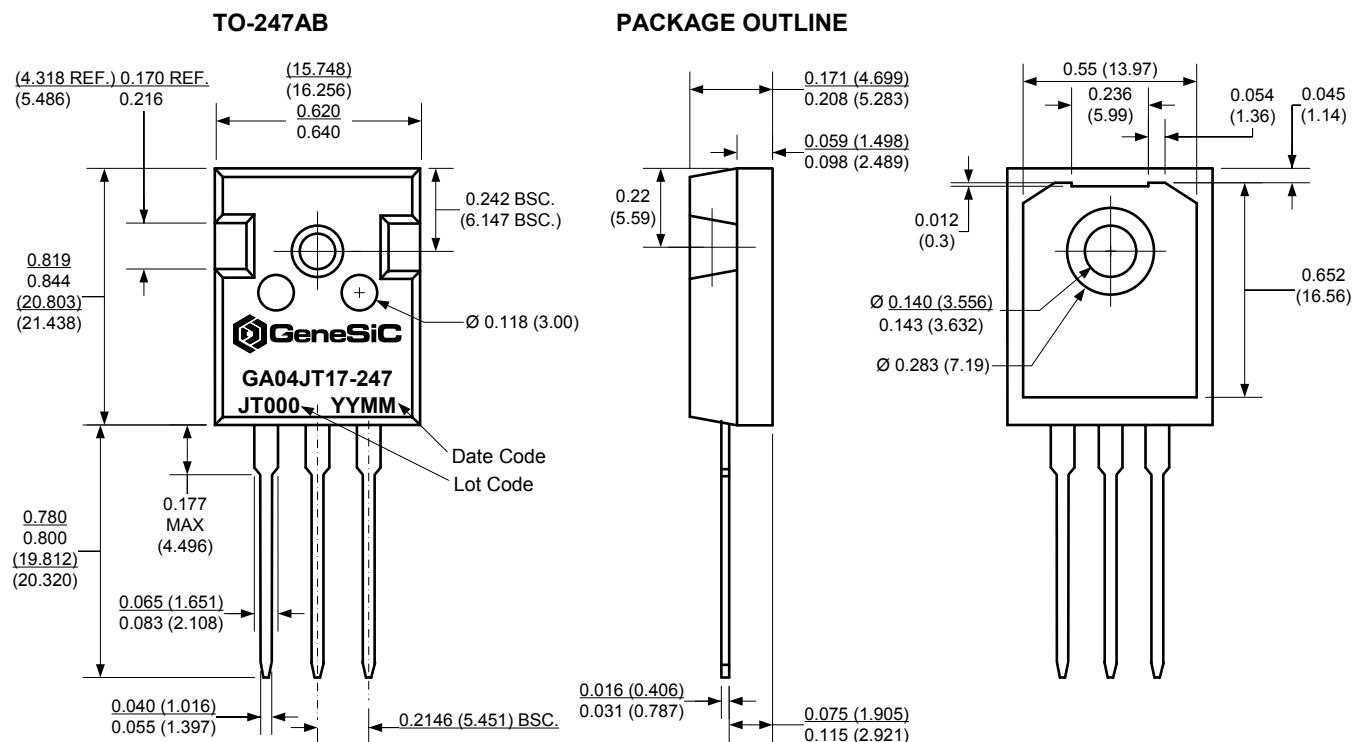
Figure 21: Recommended Gate Diver Configuration (Option #2)

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Option #2 Gate Drive Conditions (IXDD614/IXDN614)						
Supply Voltage	V _{cc}		-0.3	15	40	V
Gate Control Input Signal, Low	IN		-5.0	0	0.8	V
Gate Control Input Signal, High	IN		3.0	5.0	V _{cc} +0.3	V
Enable, Low	EN	IXDD614 Only		1/3*V _{cc}		V
Enable, High	EN	IXDD614 Only	2/3*V _{cc}			V
Output Voltage, Low	V _{out}			0.025		V
Output Voltage, High	V _{out}		V _{cc} -0.025			V
Output Current, Peak	I _{out}	Package Limited	4.5	14	A	
Output Current, Continuous	I _{out}		0.5	4.0	A	

Passive Gate Components

Gate Resistance	R _G	I _G ≈ 0.5 A	5	22	Ω
Gate Capacitance	C _G	I _G ≈ 0.5 A	9		nF

Package Dimensions:



NOTE

- NOTE**
1. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.
2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS

Revision History			
Date	Revision	Comments	Supersedes
2013/11/12	3	Updated Electrical Characteristics	
2013/06/24	2	Updated Electrical Characteristics	
2013/02/21	1	Revised electrical characteristics	
2012/12/03	0	Initial release	

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SPICE Model Parameters

Copy the following code into a SPICE software program for simulation of the GA04JT17 SJT device.

```
* MODEL OF GeneSiC Semiconductor Inc.  
*  
* $Revision: 1.0      $  
* $Date: 26-AUG-2013 $  
*  
* GeneSiC Semiconductor Inc.  
* 43670 Trade Center Place Ste. 155  
* Dulles, VA 20166  
* http://www.genesicsemi.com/index.php/sic-products/sjt  
*  
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*  
* These models are provided "AS IS, WHERE IS, AND WITH NO WARRANTY  
* OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED  
* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A  
* PARTICULAR PURPOSE."  
* Models accurate up to 2 times rated drain current.  
*  
.model GA04JT17 NPN  
+ IS      1.22E-47  
+ ISE     3.91E-27  
+ EG      3.2  
+ BF      58  
+ BR      0.55  
+ IKF     200  
+ NF      1  
+ NE      2.022  
+ RB      0.26  
+ RE      0.131970371  
+ RC      0.358  
+ CJC     1.37E-10  
+ VJC     3.173990516  
+ MJC     0.436428533  
+ CJE     3.36E-10  
+ VJE     2.944816511  
+ MJE     0.493905327  
+ XTI     3  
+ XTB     -1.16  
+ TRC1    8.00E-3  
+ VCEO    1700  
+ ICRATING 4  
+ MFG     GeneSiC_Semiconductor  
*  
* End of GA04JT17 SPICE Model
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